


## Search History


[Database Details](#)

Set	Term Searched	Items	
S1	DISLOCATION (S) LEAKAGE	483	<a href="#">Display</a>
S2	PY>2004	4573737	<a href="#">Display</a>
S3	(MISFET OR MOSFET OR NMOS OR PMOS OR FET OR CMOS)	229972	<a href="#">Display</a>
S4	CONCENTRATION (S) IMPURITY	22837	<a href="#">Display</a>
S5	S1 AND S3 AND S4	0	<a href="#">Display</a>
S6	S1 AND S4	2	<a href="#">Display</a>
S7	S1 AND S3	91	<a href="#">Display</a>
S8	S7 NOT S2	59	<a href="#">Display</a>
S9	(STRAINED OR STRAIN OR SI OR SIGE)	985945	<a href="#">Display</a>
S10	S8 AND S9	36	<a href="#">Display</a>
S11	(ISOLATION OR INSULATING OR ISULATION) AND (SUBSTRATE OR BASE)	20344	<a href="#">Display</a>
S12	(ISOLATION OR INSULATING OR ISULATION OR DIELECTRIC) AND (SUBSTRATE BASE)	0	<a href="#">Display</a>
S13	S10 AND S11	2	<a href="#">Display</a>
S14	(GATE AND (SOURCE OR DRAIN) AND DISLOCATION AND LEAKAGE AND DEPTH AND CONCENTRATION)	0	<a href="#">Display</a>
S15	(GATE AND (SOURCE OR DRAIN) AND DISLOCATION AND LEAKAGE)	33	<a href="#">Display</a>
S16	(DEPTH OR THICK OR THICKNESS OR GREATER) AND DISLOCATION	12024	<a href="#">Display</a>
S17	S16 AND CONCENTRATION	1071	<a href="#">Display</a>
S18	17 AND S3	3070	<a href="#">Display</a>
S19	S18 AND S9	508	<a href="#">Display</a>
S20	S19 AND GATE AND (SOURCE OR DRAIN)	69	<a href="#">Display</a>
S21	S20 NOT S2	57	<a href="#">Display</a>

Format

Free Number of  
Records10 

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